



Integrated Device Technology, Inc.

FAST CMOS OCTAL TRANSPARENT LATCHES

IDT54/74FCT373T/AT/CT/DT - 2373T/AT/CT

IDT54/74FCT533T/AT/CT

IDT54/74FCT573T/AT/CT/DT - 2573T/AT/CT

FEATURES:

- **Common features:**

- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- CMOS power levels
- True TTL input and output compatibility
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- Meets or exceeds JEDEC standard 18 specifications
- Product available in Radiation Tolerant and Radiation Enhanced versions
- Military product compliant to MIL-STD-883, Class B and DESC listed (dual marked)
- Available in DIP, SOIC, SSOP, QSOP, CERPACK and LCC packages

- **Features for FCT373T/FCT533T/FCT573T:**

- Std., A, C and D speed grades
- High drive outputs (-15mA I_{OH} , 48mA I_{OL})
- Power off disable outputs permit "live insertion"

- **Features for FCT2373T/FCT2573T:**

- Std., A and C speed grades
- Resistor output (-15mA I_{OH} , 12mA I_{OL} Com.)
(-12mA I_{OH} , 12mA I_{OL} Mil.)

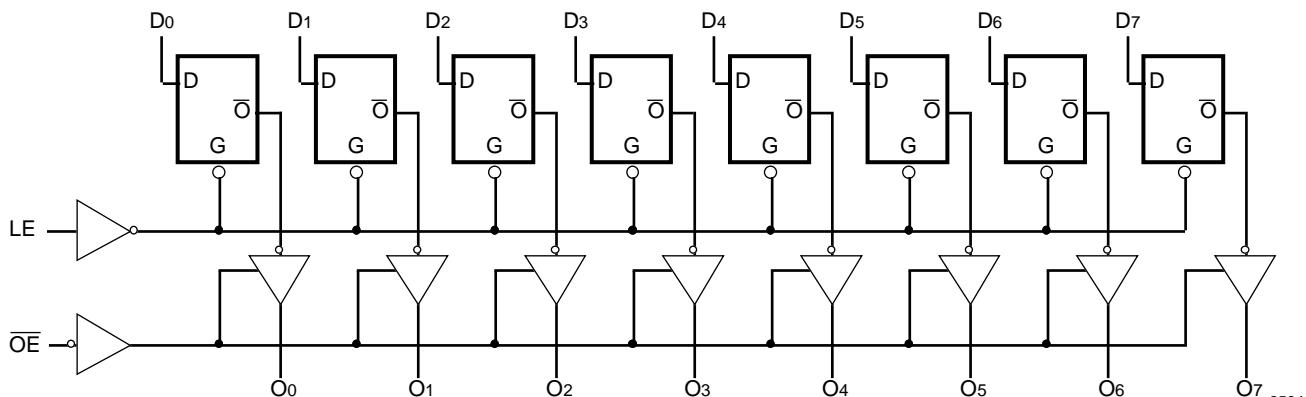
- Reduced system switching noise

DESCRIPTION:

The FCT373T/FCT2373T, FCT533T and FCT573T/FCT2573T are octal transparent latches built using an advanced dual metal CMOS technology. These octal latches have 3-state outputs and are intended for bus oriented applications. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. When LE is LOW, the data that meets the set-up time is latched. Data appears on the bus when the Output Enable (\bar{OE}) is LOW. When \bar{OE} is HIGH, the bus output is in the high-impedance state.

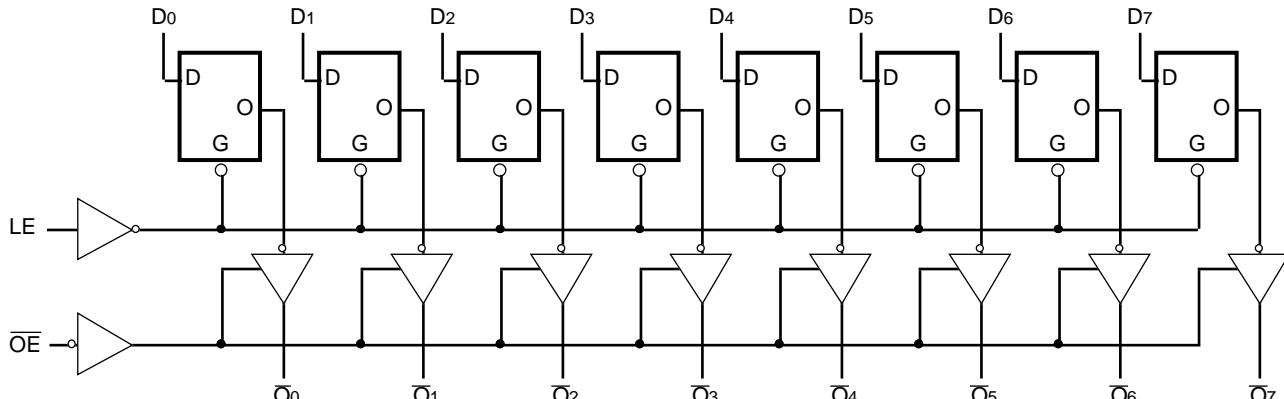
The FCT2373T and FCT2573T have balanced drive outputs with current limiting resistors. This offers low ground bounce, minimal undershoot and controlled output fall times-reducing the need for external series terminating resistors. The FCT2xxxT parts are plug-in replacements for FCTxxxT parts.

FUNCTIONAL BLOCK DIAGRAM IDT54/74FCT373T/2373T AND IDT54/74FCT573T/2573T



2564 cnv* 01

FUNCTIONAL BLOCK DIAGRAM IDT54/74FCT533T

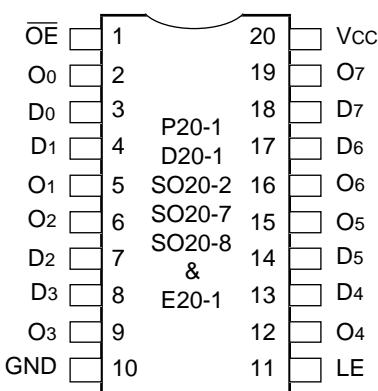


2564 cnv* 02

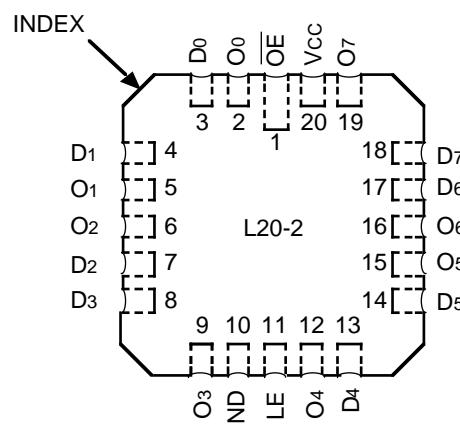
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MILITARY AND COMMERCIAL TEMPERATURE RANGES

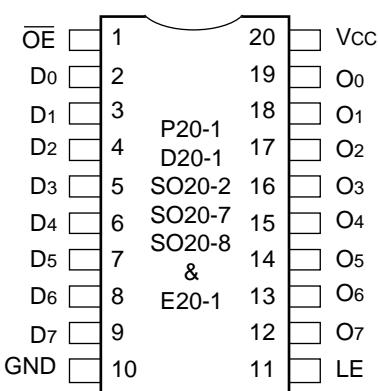
AUGUST 1995

PIN CONFIGURATIONS**IDT54/74FCT373/2373T**

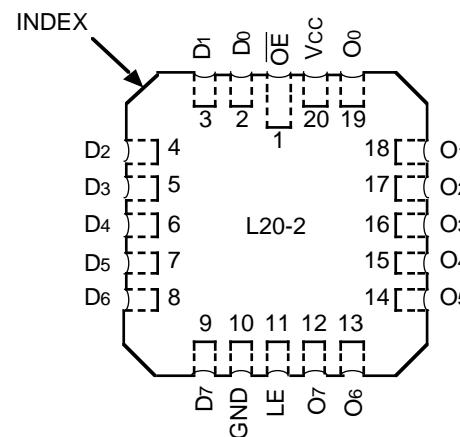
2564 cnv* 03

DIP/SOIC/SSOP/QSOP/CERPACK
TOP VIEW

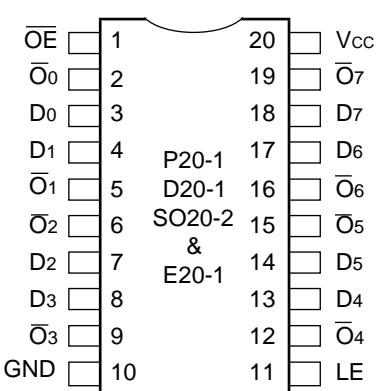
2564 cnv* 04

LCC
TOP VIEW**IDT54/74FCT573/2573T**

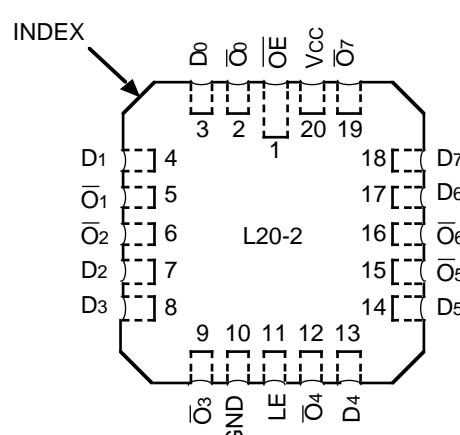
2564 cnv* 05

DIP/SOIC/SSOP/QSOP/CERPACK
TOP VIEW

2564 cnv* 06

LCC
TOP VIEW**IDT54/74FCT533**

2564 cnv* 07

DIP/SOIC/CERPACK
TOP VIEW

2564 cnv* 08

LCC
TOP VIEW

FUNCTION TABLE (533)⁽¹⁾

Inputs		Outputs	
DN	LE	\overline{OE}	\overline{ON}
H	H	L	L
L	H	L	H
X	X	H	Z

NOTE:

2564 tbl 01

1. H = HIGH Voltage Level
- L = LOW Voltage Level
- X = Don't Care
- Z = High Impedance

FUNCTION TABLE (373 and 573)⁽¹⁾

Inputs		Outputs	
DN	LE	\overline{OE}	\overline{ON}
H	H	L	H
L	H	L	L
X	X	H	Z

NOTE:

2564 tbl 02

1. H = HIGH Voltage Level
- L = LOW Voltage Level
- X = Don't Care
- Z = High Impedance

DEFINITION OF FUNCTIONAL TERMS

Pin Names	Description
DN	Data Inputs
LE	Latch Enable Input (Active HIGH)
\overline{OE}	Output Enable Input (Active LOW)
ON	3-State Outputs
\overline{ON}	Complementary 3-State Outputs

2564tbl 03

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Rating	Commercial	Military	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
VTERM ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to Vcc +0.5	-0.5 to Vcc +0.5	V
TA	Operating Temperature	0 to +70	-55 to +125	°C
TBIAS	Temperature Under Bias	-55 to +125	-65 to +135	°C
TSTG	Storage Temperature	-55 to +125	-65 to +150	°C
PT	Power Dissipation	0.5	0.5	W
IOUT	DC Output Current	-60 to +120	-60 to +120	mA

2564 Ink 04

NOTES:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed Vcc by +0.5V unless otherwise noted.
2. Input and Vcc terminals only.
3. Outputs and I/O terminals only.

CAPACITANCE (TA = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	8	12	pF

2564 Ink 05

1. This parameter is measured at characterization but not tested.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: TA = 0°C to +70°C, VCC = 5.0V ± 5%; Military: TA = -55°C to +125°C, VCC = 5.0V ± 10%

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
VIH	Input HIGH Level	Guaranteed Logic HIGH Level		2.0	—	—	V
VIL	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I _{IH}	Input HIGH Current ⁽⁴⁾	VCC = Max.	VI = 2.7V	—	—	±1	μA
I _{IL}	Input LOW Current ⁽⁴⁾		VI = 0.5V	—	—	±1	
I _{OZH}	High Impedance Output Current (3-State Output pins) ⁽⁴⁾	VCC = Max.	VO = 2.7V	—	—	±1	μA
I _{OZL}			VO = 0.5V	—	—	±1	
I _I	Input HIGH Current ⁽⁴⁾	VCC = Max., VI = VCC (Max.)		—	—	±1	μA
V _{IK}	Clamp Diode Voltage	VCC = Min., I _{IN} = -18mA		—	-0.7	-1.2	V
V _H	Input Hysteresis	—		—	200	—	mV
I _{CC}	Quiescent Power Supply Current	VCC = Max., V _{IN} = GND or VCC		—	0.01	1	mA

2564 Ink 06

OUTPUT DRIVE CHARACTERISTICS FOR FCT373T/533T/573T

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V _{OH}	Output HIGH Voltage	VCC = Min. VIN = VIH or VIL	I _{OH} = -6mA MIL. I _{OH} = -8mA COM'L.	2.4	3.3	—	V
			I _{OH} = -12mA MIL. I _{OH} = -15mA COM'L.	2.0	3.0	—	V
V _{OL}	Output LOW Voltage	VCC = Min. VIN = VIH or VIL	I _{OL} = 32mA MIL. I _{OL} = 48mA COM'L.	—	0.3	0.5	V
I _{OS}	Short Circuit Current	VCC = Max., VO = GND ⁽³⁾		-60	-120	-225	mA
I _{OFF}	Input/Output Power Off Leakage ⁽⁵⁾	VCC = 0V, VIN or VO ≤ 4.5V		—	—	±1	μA

2564 Ink 07

OUTPUT DRIVE CHARACTERISTICS FOR FCT2373T/2573T

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
I _{ODL}	Output LOW Current	VCC = 5V, VIN = VIH or VIL, VOUT = 1.5V ⁽³⁾		16	48	—	mA
I _{ODH}	Output HIGH Current	VCC = 5V, VIN = VIH or VIL, VOUT = 1.5V ⁽³⁾		-16	-48	—	mA
V _{OH}	Output HIGH Voltage	VCC = Min. VIN = VIH or VIL	I _{OH} = -12mA MIL. I _{OH} = -15mA COM'L.	2.4	3.3	—	V
V _{OL}	Output LOW Voltage	VCC = Min. VIN = VIH or VIL	I _{OL} = 12mA	—	0.3	0.50	V

NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at VCC = 5.0V, +25°C ambient.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
- The test limit for this parameter is ±5μA at TA = -55°C.
- This parameter is guaranteed but not tested.

2564 Ink 08

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾			Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$			—	0.5	2.0	mA
I _{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}$ Outputs Open $\overline{OE} = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	FCT $xxxT$	—	0.15	0.25	mA/ MHz
				FCT2 $xxxT$	—	0.06	0.12	
I _C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}$ Outputs Open $f_i = 10\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ $LE = V_{CC}$ One Bit Toggling	$V_{IN} = V_{CC}$	FCT $xxxT$	—	1.5	3.5	mA
				FCT2 $xxxT$	—	0.6	2.2	
			$V_{IN} = 3.4$ $V_{IN} = \text{GND}$	FCT $xxxT$	—	1.8	4.5	
				FCT2 $xxxT$	—	0.9	3.2	
		$V_{CC} = \text{Max.}$ Outputs Open $f_i = 2.5\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ $LE = V_{CC}$ Eight Bits Toggling	$V_{IN} = V_{CC}$	FCT $xxxT$	—	3.0	6.0 ⁽⁵⁾	
				FCT2 $xxxT$	—	1.2	3.4 ⁽⁵⁾	
			$V_{IN} = 3.4$ $V_{IN} = \text{GND}$	FCT $xxxT$	—	5.0	14.0 ⁽⁵⁾	
				FCT2 $xxxT$	—	3.2	11.4 ⁽⁵⁾	

NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0V$, $+25^{\circ}\text{C}$ ambient.
- Per TTL driven input ($V_{IN} = 3.4V$). All other inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$

$$I_C = I_{CC} + \Delta I_{CC} D_{HNT} + I_{CCD} (f_{CP}/2 + f_i N_i)$$

I_{CC} = Quiescent Current

ΔI_{CC} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)

f_i = Input Frequency

N_i = Number of Inputs at f_i

All currents are in millamps and all frequencies are in megahertz.

2564 tbl 09

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Symbol	Parameter	Conditions ⁽¹⁾	FCT373T/2373T/573T/2573T				FCT373AT/2373AT/573AT/2573AT				Unit	
			Com'l.		Mil.		Com'l.		Mil.			
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.		
tPLH tPHL	Propagation Delay DN to ON	CL = 50pF RL = 500Ω	1.5	8.0	1.5	8.5	1.5	5.2	1.5	5.6	ns	
tPLH tPHL	Propagation Delay LE to ON		2.0	13.0	2.0	15.0	2.0	8.5	2.0	9.8	ns	
tPZH tPZL	Output Enable Time		1.5	12.0	1.5	13.5	1.5	6.5	1.5	7.5	ns	
tPHZ tPLZ	Output Disable Time		1.5	7.5	1.5	10.0	1.5	5.5	1.5	6.5	ns	
tsU	Set-up Time HIGH or LOW, DN to LE		2.0	—	2.0	—	2.0	—	2.0	—	ns	
tH	Hold Time HIGH or LOW, DN to LE		1.5	—	1.5	—	1.5	—	1.5	—	ns	
tw	LE Pulse Width HIGH		6.0	—	6.0	—	5.0	—	6.0	—	ns	

2564 tbl 10

Symbol	Parameter	Conditions ⁽¹⁾	FCT373CT/2373CT/573CT/2573CT				FCT373DT/573DT				Unit	
			Com'l.		Mil.		Com'l.		Mil.			
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.		
tPLH tPHL	Propagation Delay DN to ON	CL = 50pF RL = 500Ω	1.5	4.2	1.5	5.1	1.5	3.8	—	—	ns	
tPLH tPHL	Propagation Delay LE to ON		2.0	5.5	2.0	8.0	2.0	4.0	—	—	ns	
tPZH tPZL	Output Enable Time		1.5	5.5	1.5	6.3	1.5	4.8	—	—	ns	
tPHZ tPLZ	Output Disable Time		1.5	5.0	1.5	5.9	1.5	4.0	—	—	ns	
tsU	Set-up Time HIGH or LOW, DN to LE		2.0	—	2.0	—	1.5	—	—	—	ns	
tH	Hold Time HIGH or LOW, DN to LE		1.5	—	1.5	—	1.0	—	—	—	ns	
tw	LE Pulse Width HIGH ⁽³⁾		5.0	—	6.0	—	3.0	—	—	—	ns	

2564 tbl 10

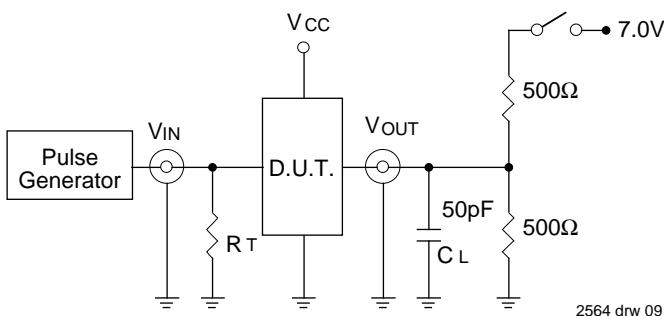
Symbol	Parameter	Conditions ⁽¹⁾	FCT533T				FCT533AT				FCT533CT				Unit	
			Com'l.		Mil.		Com'l.		Mil.		Com'l.		Mil.			
			Min. ⁽²⁾	Max.												
tPLH tPHL	Propagation Delay DN to $\bar{O}N$	CL = 50pF RL = 500Ω	1.5	10.0	1.5	12.0	1.5	5.2	1.5	5.6	1.5	4.2	1.5	5.1	ns	
tPLH tPHL	Propagation Delay LE to $\bar{O}N$		2.0	13.0	2.0	14.0	2.0	8.5	2.0	9.8	2.0	5.5	2.0	8.0	ns	
tPZH tPZL	Output Enable Time		1.5	11.0	1.5	12.5	1.5	6.5	1.5	7.5	1.5	5.5	1.5	6.3	ns	
tPHZ tPLZ	Output Disable Time		1.5	7.0	1.5	8.5	1.5	5.5	1.5	6.5	1.5	5.0	1.5	5.9	ns	
tsU	Set-up Time HIGH or LOW, DN to LE		2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	ns	
tH	Hold Time HIGH or LOW, DN to LE		1.5	—	1.5	—	1.5	—	1.5	—	1.5	—	1.5	—	ns	
tw	LE Pulse Width HIGH		6.0	—	6.0	—	5.0	—	6.0	—	5.0	—	6.0	—	ns	

2564 tbl 11

NOTES:
 1. See test circuit and waveforms.
 2. Minimum limits are guaranteed but not tested on Propagation Delays.
 3. This parameter is guaranteed but not tested.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

Test	Switch
Open Drain	Closed
Disable Low	
Enable Low	
All Other Tests	Open

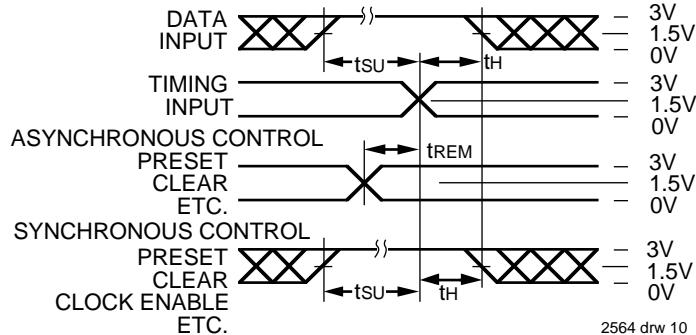
DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.

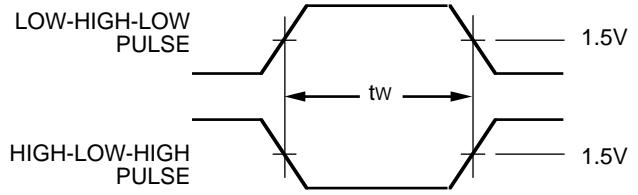
RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

2564 drw 13

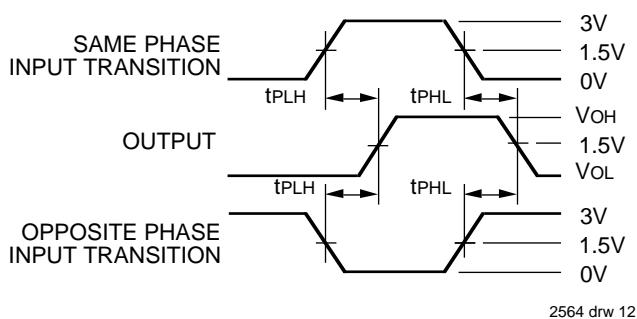
SET-UP, HOLD AND RELEASE TIMES



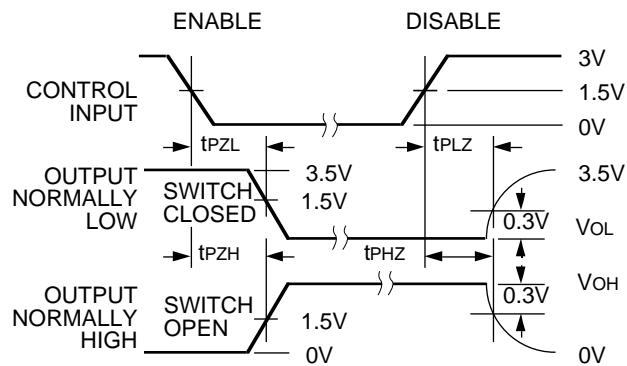
PULSE WIDTH



PROPAGATION DELAY



ENABLE AND DISABLE TIMES



NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
2. Pulse Generator for All Pulses: Rate \leq 1.0MHz; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$

ORDERING INFORMATION

